

<b>Notice of References Cited</b>	Application/Control No. 10/751,288	Applicant(s)/Patent Under Reexamination LIN, YEN-WEN	
	Examiner Alvin J Grant	Art Unit 3723	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,148,698	11-2000	Hsieh, Chih-Ching	81/177.8
	B	US-5,916,339	06-1999	Dumont, Bertrand	81/63.1
	C	US-6,745,650	06-2004	Chang, Tsung-Chieh	81/177.8
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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